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December 2008

FDS8878 N-Channel PowerTrench® MOSFET

30V, 10.2A, 14mΩ

Features

- $r_{DS(on)}$ = 14m Ω , V_{GS} = 10V, I_D = 10.2A
- \blacksquare r_{DS(on)} = 17m Ω , V_{GS} = 4.5V, I_D = 9.3A
- High performance trench technology for extremely low r_{DS(on)}
- Low gate charge
- High power and current handling capability
- RoHS Compliant



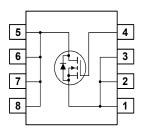
General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\text{DS}(\text{on})}$ and fast switching speed.

Applications

■ DC/DC converters





mW/°C

٥С

-55 to 150

MOSFET Maximum Ratings T _A = 25°C unless otherwise noted				
Symbol	Parameter	Ratings	Units	
$V_{\rm DSS}$	Drain to Source Voltage	30	V	
V_{GS}	Gate to Source Voltage	±20	V	
	Drain Current			
	Continuous ($T_A = 25^{\circ}C$, $V_{GS} = 10V$, $R_{\theta JA} = 50^{\circ}C/W$)	10.2	Α	
ID	Continuous ($T_A = 25^{\circ}C$, $V_{GS} = 4.5V$, $R_{\theta JA} = 50^{\circ}C/W$)	9.3	Α	
	Pulsed	80	Α	
E _{AS}	Single Pulse Avalanche Energy (Note 1)	57	mJ	
	Power dissipation	2.5	W	

Thermal Characteristics

Derate above 25°C

 P_{D}

T_J, T_{STG}

$R_{\theta JC}$	Thermal Resistance, Junction to Case (Note 2)	25	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 2a)	50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 2b)	125	°C/W

Package Marking and Ordering Information

Operating and Storage Temperature

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS8878	FDS8878	SO-8	330mm	12mm	2500 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter Test Conditions		Min	Тур	Max	Units
Off Chara	cteristics					
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30	-	-	V
1	Zero Gate Voltage Drain Current	V _{DS} = 24V	-	-	1	
IDSS	Zero Gate voltage Drain Current	$V_{GS} = 0V$ $T_J = 150^{\circ}C$	-	-	250	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	-	-	±100	nA

On Characteristics

V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	-	2.5	V
		$I_D = 10.2A, V_{GS} = 10V$	-	11.0	14.0	
r _{DS(on)} Drain to Source On Resistance	Drain to Source On Pesistance	$I_D = 9.3A, V_{GS} = 4.5V$	-	13.8	17.0	mΩ
	$I_D = 10.2A, V_{GS} = 10V,$ $T_J = 150^{\circ}C$	-	17.5	22.7	11152	

Dynamic Characteristics

C _{ISS}	Input Capacitance	\/ - 15\/ \/ - 0\/	-	897	-	pF
Coss	Output Capacitance	V _{DS} = 15V, V _{GS} = 0V, f = 1MHz	-	190	-	pF
C _{RSS}	Reverse Transfer Capacitance	1 - 11/11/2	-	111	-	pF
R_G	Gate Resistance	$V_{GS} = 0.5V, f = 1MHz$	0.7	2.9	5.0	Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	V _{GS} = 0V to 10V	ı	17	26	nC
$Q_{g(5)}$	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$ $V_{DD} = 15V$ $I_{D} = 10.2A$	ı	9	14	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 1V$ $I_{G} = 1.0 \text{mA}$	ı	0.9	1.4	nC
Q_{gs}	Gate to Source Gate Charge	- g	-	2.5	-	nC
Q_{gs2}	Gate Charge Threshold to Plateau		-	1.7	-	nC
Q_{gd}	Gate to Drain "Miller" Charge		-	3.3	-	nC

Switching Characteristics ($V_{GS} = 10V$)

t _{ON}	Turn-On Time		-	-	54	ns
t _{d(ON)}	Turn-On Delay Time		-	7	-	ns
t _r	Rise Time	V _{DD} = 15V, I _D = 10.2A	-	29	-	ns
t _{d(OFF)}	Turn-Off Delay Time	V_{GS} = 10V, R_{GS} = 16 Ω	-	45	-	ns
t _f	Fall Time		-	18	-	ns
t _{OFF}	Turn-Off Time]	-	-	94	ns

Drain-Source Diode Characteristics

V	Source to Drain Diode Voltage	I _{SD} = 10.2A	-	-	1.25	V
v_{SD}	Source to Drain Diode voltage	I _{SD} = 2.1A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 10.2A$, $dI_{SD}/dt = 100A/\mu s$	-	-	19	ns
Q_{RR}	Reverse Recovered Charge	$I_{SD} = 10.2A$, $dI_{SD}/dt = 100A/\mu s$	-	-	9.5	nC

- Starting T_J = 25°C, L = 1mH, I_{AS} = 10.7A, V_{DD} = 30V, V_{GS} = 10V.
 R_{0,IA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0,IC} is guaranteed by design while R_{0,IA} is determined by the user's board design.

 a) 50°C/W when mounted on a 1in² pad of 2 oz copper.
 - b) 125°C/W when mounted on a minimum pad.

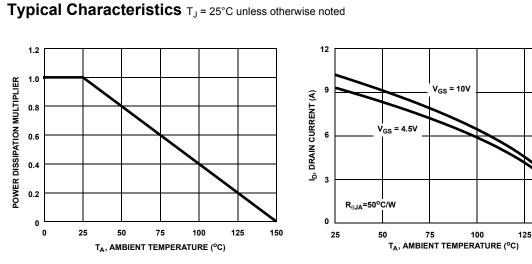


Figure 1. Normalized Power Dissipation vs
Ambient Temperature

Figure 2. Maximum Continuous Drain Current vs
Ambient Temperature

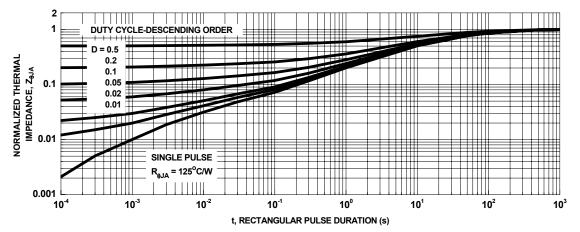


Figure 3. Normalized Maximum Transient Thermal Impedance

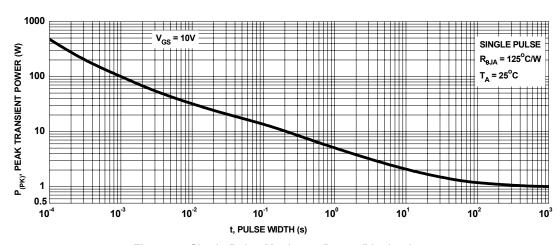
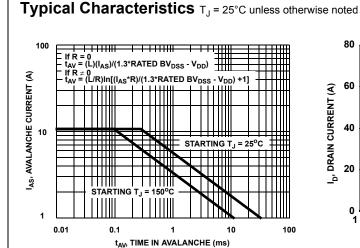


Figure 4. Single Pulse Maximum Power Dissipation



D, DRAIN CURRENT (A) $T{\rm J} = 25^{\circ}{\rm C}$ 20 $T_J = 150$ °C 0 1 2 5 V_{GS}, GATE TO SOURCE VOLTAGE (V)

PULSE DURATION = 80μs DUTY CYCLE = 0.5%MAX

80

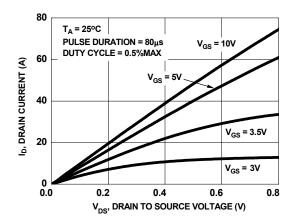
60

40

 $V_{DS} = 5V$

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515 **Figure 5. Unclamped Inductive Switching** Capability

Figure 6. Transfer Characteristics



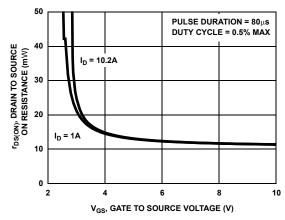
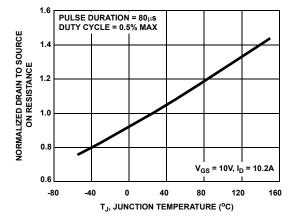


Figure 7. Saturation Characteristics

Figure 8. Drain to Source On Resistance vs Gate **Voltage and Drain Current**



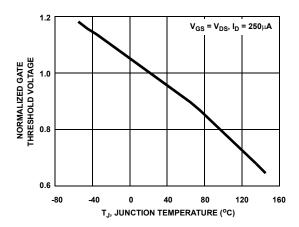


Figure 9. Normalized Drain to Source On **Resistance vs Junction Temperature**

Figure 10. Normalized Gate Threshold Voltage vs **Junction Temperature**

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

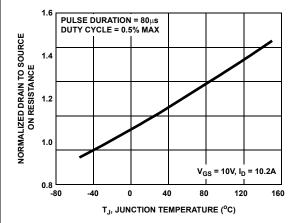
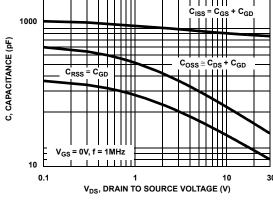


Figure 11. Normalized Drain to Source Breakdown Voltage vs Junction Temperature



2000

Figure 12. Capacitance vs Drain to Source Voltage

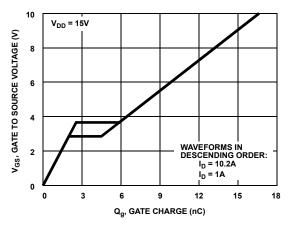


Figure 13. Gate Charge Waveforms for Constant Gate Currents

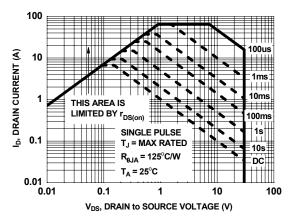
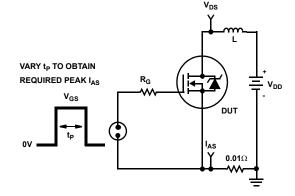


Figure 14. Forward Bias Safe Operating Area

Test Circuits and Waveforms



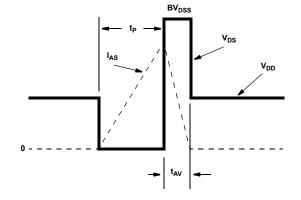


Figure 15. Unclamped Energy Test Circuit

Figure 16. Unclamped Energy Waveforms

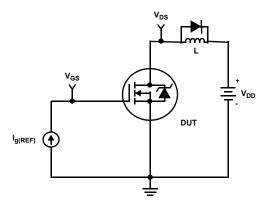


Figure 17. Gate Charge Test Circuit

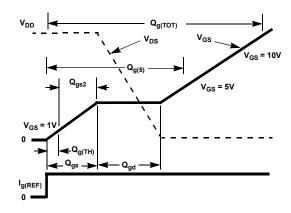


Figure 18. Gate Charge Waveforms

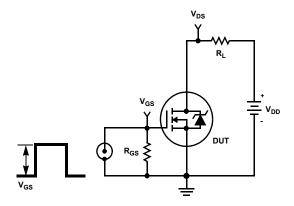


Figure 19. Switching Time Test Circuit

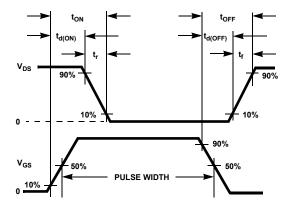


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
 (EQ. 1)

In using surface mount devices such as the SO8 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- The number of copper layers and the thickness of the board
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient

thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2. The area, in square inches is the top copper area including the gate and source pads.

$$R_{\theta JA} = 64 + \frac{26}{0.23 + Area}$$
 (EQ. 2)

The transient thermal impedance $(Z_{\theta JA})$ is also effected by varied top copper board area. Figure 22 shows the effect of copper pad area on single pulse transient thermal impedance. Each trace represents a copper pad area in square inches corresponding to the descending list in the graph. Spice and SABER thermal models are provided for each of the listed pad areas.

Copper pad area has no perceivable effect on transient thermal impedance for pulse widths less than 100ms. For pulse widths less than 100ms the transient thermal impedance is determined by the die and package. Therefore, CTHERM1 through CTHERM5 and RTHERM1 through RTHERM5 remain constant for each of the thermal models. A listing of the model component values is available in Table 1.

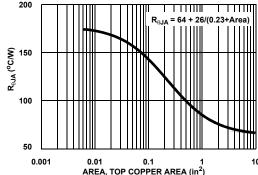


Figure 21. Thermal Resistance vs Mounting
Pad Area

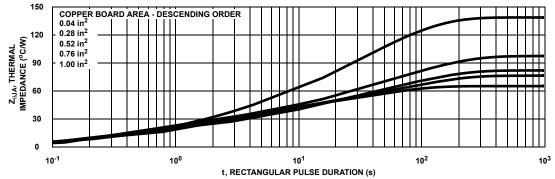


Figure 22. Thermal Impedance vs Mounting Pad Area

PSPICE Electrical Model .SUBCKT FDS8878 2 1 3 *February 2005 Ca 12 8 7.8e-10 Cb 15 14 7.8e-10 LDRAIN DPLCAP Cin 6 8 .78e-9 DRAIN Dbody 7 5 DbodyMOD 10 Dbreak 5 11 DbreakMOD **RLDRAIN** RSLC1 Dplcap 10 5 DplcapMOD DBREAK RSLC2 Ebreak 11 7 17 18 32.9 **ESLC** 11 Fds 14 8 5 8 1 50 Eas 13 8 6 8 1 Esq 6 10 6 8 1 DBODY RDRAIN EBREAK 8 **ESG** Evthres 6 21 19 8 1 **EVTHRES** Evtemp 20 6 18 22 1 $\frac{19}{8}$ **←** MWEAK **LGATE EVTEMP** RGATE It 8 17 1 GATE 18 22 MMED J9 20 MSTRO Lgate 1 9 5.29e-9 RLGATE Ldrain 2 5 1.0e-9 LSOURCE CIN SOURCE Lsource 3 7 0.18e-9 RSOURCE RLgate 1 9 52.9 RLSOURCE RLdrain 2 5 10 RBREAK RLsource 3 7 1.8 14 13 <u>13</u> 8 17 18 Mmed 16 6 8 8 MmedMOD **₹**RVTEMP S₁B oS2B Mstro 16 6 8 8 MstroMOD СВ 19 CA Mweak 16 21 8 8 MweakMOD IT 14 (♠ VBAT 8 EGS EDS Rbreak 17 18 RbreakMOD 1 Rdrain 50 16 RdrainMOD 1.6e-3 Rgate 9 20 2.3 **RVTHRES** RŠLC1 5 51 RSLCMOD 1e-6 RSLC2 5 50 1e3 Rsource 8 7 RsourceMOD 8.9e-3 Rvthres 22 8 RvthresMOD 1 Rvtemp 18 19 RvtempMOD 1 S1a 6 12 13 8 S1AMOD S1b 13 12 13 8 S1BMOD S2a 6 15 14 13 S2AMOD S2b 13 15 14 13 S2BMOD Vbat 22 19 DC 1 ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*170),5))} .MODEL DbodyMOD D (IS=2.0E-12 IKF=10 N=1.01 RS=7.0e-3 TRS1=8e-4 TRS2=2e-7 + CJO=3.5e-10 M=0.55 TT=7e-11 XTI=2) .MODEL DbreakMOD D (RS=0.2 TRS1=1e-3 TRS2=-8.9e-6) .MODEL DplcapMOD D (CJO=3.8e-10 IS=1e-30 N=10 M=0.45) .MODEL MstroMOD NMOS (VTO=2.36 KP=150 IS=1e-30 N=10 TOX=1 L=1u W=1u) .MODEL MmedMOD NMOS (VTO=1.95 KP=5.0 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=2.3) .MODEL MweakMOD NMOS (VTO=1.57 KP=0.02 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=23 RS=0.1) .MODEL RbreakMOD RES (TC1=8.3e-4 TC2=-8e-7) MODEL RdrainMOD RES (TC1=15e-3 TC2=0.1e-5) .MODEL RSLCMOD RES (TC1=1e-4 TC2=1e-6) .MODEL RsourceMOD RES (TC1=1e-3 TC2=3e-6) .MODEL RvtempMOD RES (TC1=-1.8e-3 TC2=2e-7) .MODEL RythresMOD RES (TC1=-2.0e-3 TC2=-6e-6) MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-4 VOFF=-3.5) .MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-3.5 VOFF=-4) .MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-1.5 VOFF=-1.0) .MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-1.0 VOFF=-1.5).ENDSNote: For further discussion of the PSPICE model, consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

SABER Electrical Model **REV February 2005** template FDS8878 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=2.0e-12,ikf=10,nl=1.01,rs=7.0e-3,trs1=8e-4,trs2=2e-7,cjo=3.5e-10,m=0.55,tt=7e-11,xti=2) dp..model dbreakmod = (rs=0.2.trs1=1e-3.trs2=-8.9e-6) dp..model dplcapmod = (cjo=3.8e-10,isl=10e-30,nl=10,m=0.45) $m.model mstrongmod = (type=_n, vto=2.36, kp=150, is=1e-30, tox=1)$ m..model mmedmod = $(type=_n, vto=1.95, kp=5.0, is=1e-30, tox=1)$ m..model mweakmod = $(type=_n, vto=1.57, kp=0.02, is=1e-30, tox=1, rs=0.1)$ LDRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-4,voff=-3.5) DPLCAP DRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-3.5,voff=-4) 10 sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-1.5,voff=-1.0) RLDRAIN €RSLC1 sw vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-1.0,voff=-1.5) 51 c.ca n12 n8 = 7.8e-10RSLC2 ₹ c.cb n15 n14 = 7.8e-10 ISCL c.cin n6 n8 = .78e-9DBREAK 3 50 dp.dbody n7 n5 = model=dbodymod ≨rdrain 8 dp.dbreak n5 n11 = model=dbreakmod ESG DBODY **EVTHRES** dp.dplcap n10 n5 = model=dplcapmod (<u>19</u>) **MWEAK** LGATE **EVTEMP** spe.ebreak n11 n7 n17 n18 = 32.9_{GATE} RGATE 18 22 EBREAK **←**MMED spe.eds n14 n8 n5 n8 = 1 20 MSTRO spe.egs n13 n8 n6 n8 = 1 RLGATE spe.esg n6 n10 n6 n8 = 1 LSOURCE CIN spe.evthres n6 n21 n19 n8 = 1 SOURCE spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1RBREAK 17 18 I.lgate n1 n9 = 5.29e-9I.ldrain n2 n5 = 1.0e-9 **≨**RVTFMP I.Isource n3 n7 = 0.18e-9СВ 19 IT res.rlgate n1 n9 = 52.9 VBAT res.rldrain n2 n5 = 10 8 **EGS EDS** res.rlsource n3 n7 = 1.8 22 RVTHRES m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u res.rbreak n17 n18 = 1, tc1=8.3e-4,tc2=-8e-7 res.rdrain n50 n16 = 1.6e-3, tc1=15e-3,tc2=0.1e-5 res.rgate n9 n20 = 2.3 res.rslc1 n5 n51 = 1e-6, tc1=1e-4,tc2=1e-6 res.rslc2 n5 n50 = 1e3 res.rsource n8 n7 = 8.9e-3, tc1=1e-3,tc2=3e-6 res.rvthres n22 n8 = 1, tc1=-2.0e-3,tc2=-6e-6 res.rvtemp n18 n19 = 1, tc1=-1.8e-3,tc2=2e-7 sw vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl |sc| = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/170))** 5))

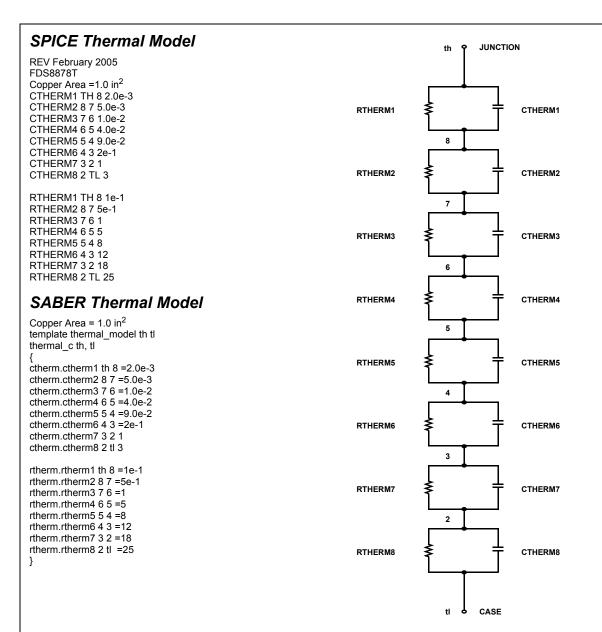


TABLE 1. THERMAL MODELS

COMPONANT	0.04 in ²	0.28 in ²	0.52 in ²	0.76 in ²	1.0 in ²
CTHERM6	1.2e-1	1.5e-1	2.0e-1	2.0e-1	2.0e-1
CTHERM7	0.5	1.0	1.0	1.0	1.0
CTHERM8	1.3	2.8	3.0	3.0	3.0
RTHERM6	26	20	15	13	12
RTHERM7	39	24	21	19	18
RTHERM8	55	38.7	31.3	29.7	25





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